

非開示情報

Certificate Of Analysis

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Manufacture Date: 05.06.2025

Customer No:

Customer order No: 非開示情報

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Customer product No

Shipping Date: 2025/06/26/

Quantity: 24000 KG

Date of print: 28.06.2025

Silicon Tetrachloride For OVD and VAD Technology

Properties	Specification	Min detectable value	Batch Values	Units
at GC				
SiCl ₄ purity	>99.99	0.0001	>99.99	%
Trichlorosilane(SiHCl ₃)	<5	1	<5	wppm
Dichlorosilane(SiH ₂ Cl ₂)	<5	1	<5	wppm
Hydrogen chloride(HCl)	<10	1	<10	wppm
at ICP-MS				
Metal Impurity (Fe)	<5	0.01	<1	wppb
Metal Impurity (Ni)	<5	0.01	<1	wppb
Metal Impurity (Cr)	<5	0.01	<1	wppb
Metal Impurity (Cu)	<5	0.01	<1	wppb
Metal Impurity (Al)	<5	0.01	<1	wppb
Metal Impurity (Mn)	<5	0.01	<1	wppb
Metal Impurity (Co)	<5	0.01	<1	wppb
Metal Impurity (Zn)	<5	0.01	<1	wppb
Metal Impurity (Ti)	<5	0.01	<1	wppb

Analysis Time: 06.06.2025

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